

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	108	substrate with round and (resistance or impedance) with measur\$4 and ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:20
S2	243	wafer and (resistance or impedance) with measur\$4 and contact near3 ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:41
S3	22815	leedy.in. or kwon.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:41
S4	43	S3 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 12:34
S5	4	((resistance or impedance) with measur\$4) same (probe adj card or interposer) same (recess or ring or slot or indented or indentation)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 12:39
S6	9835	324/754,755,757,758,765.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 12:40
S7	931	S6 and (resistance or impedance) with measur\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 12:41
S8	75	S7 and active with circuit\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:00

S9	174	probe adj card same (self-test or self adj test or calibrat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:31
S10	32	interposer same (self-test or self adj test or calibrat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:20
S11	8444	measur\$4 with (resistance or impedance) same (self-test or self adj test or calibrat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:20
S12	2698	S11 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:23
S13	69272	"324"/\$.ccls.	USPAT	OR	ON	2006/02/01 13:24
S14	699	S12 and S13	USPAT	OR	ON	2006/02/01 13:25
S15	37	S14 and substrate and ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:31
S16	9	probe adj board same (self-test or self adj test or calibrat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:34
S17	259	substrate with (active or measur\$5 with circuit\$2) same (self-test or self adj test or calibrat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 14:21
S18	46	contact adj resistance with measur\$5 and electroplat\$3 and ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 14:22

S19	12	("4461690" "4479980" "4642173" "6001235" "6004440" "6071388" "6071399" "6139712" "6156167" "6179983").PN. OR ("6517689").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/02/01 14:48
S20	198	204/228.6.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 14:49
S21	1174	204/224R.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 16:03
S22	120	S21 and (contact with (resistance or impedance or conductance or conductivity))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 16:12
S23	38	S21 and (measur\$5 with (resistance or impedance or conductance or conductivity))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 16:14
S24	11	S23 not S22	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 16:13
S25	1870	204/228.1,229.8.ccls. or 205/81,82, 83,123,157.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 16:14
S26	407	S25 and ((measur\$5 or contact) with (resistance or impedance or conductance or conductivity))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 16:15
S27	390	S26 not (S22 or S23)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 16:21